



Small Crack Fatigue Growth and Detection Modeling with Uncertainty and Acoustic Emission Application

Presentation at the
ITISE 2016 Conference, Granada, Spain
June 26th – 29th, 2016



Outline



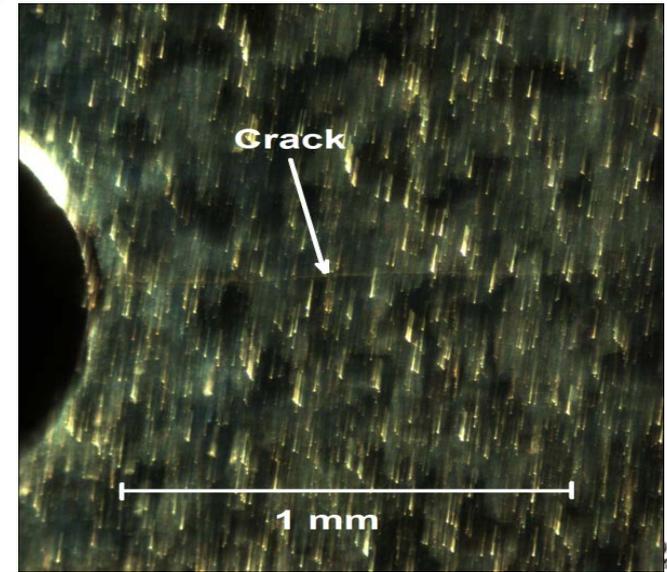
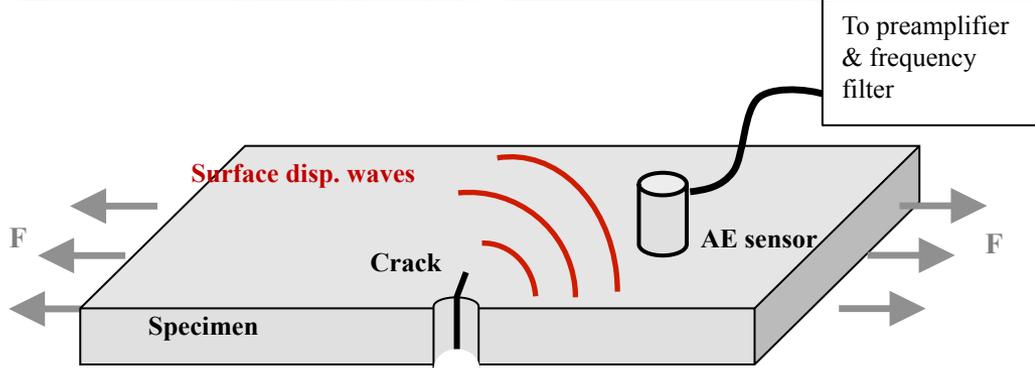
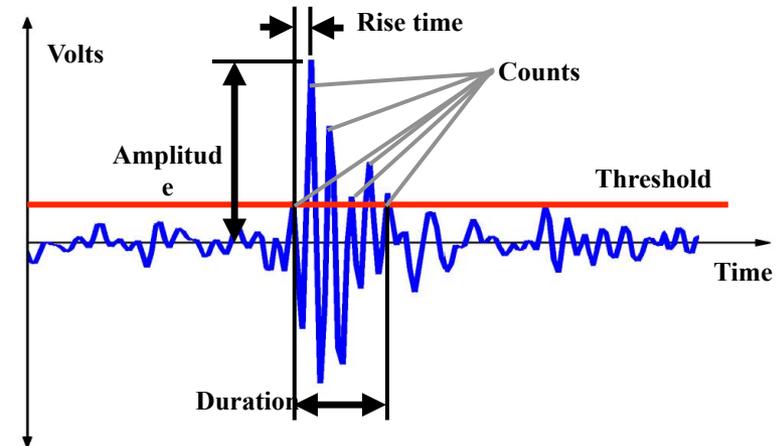
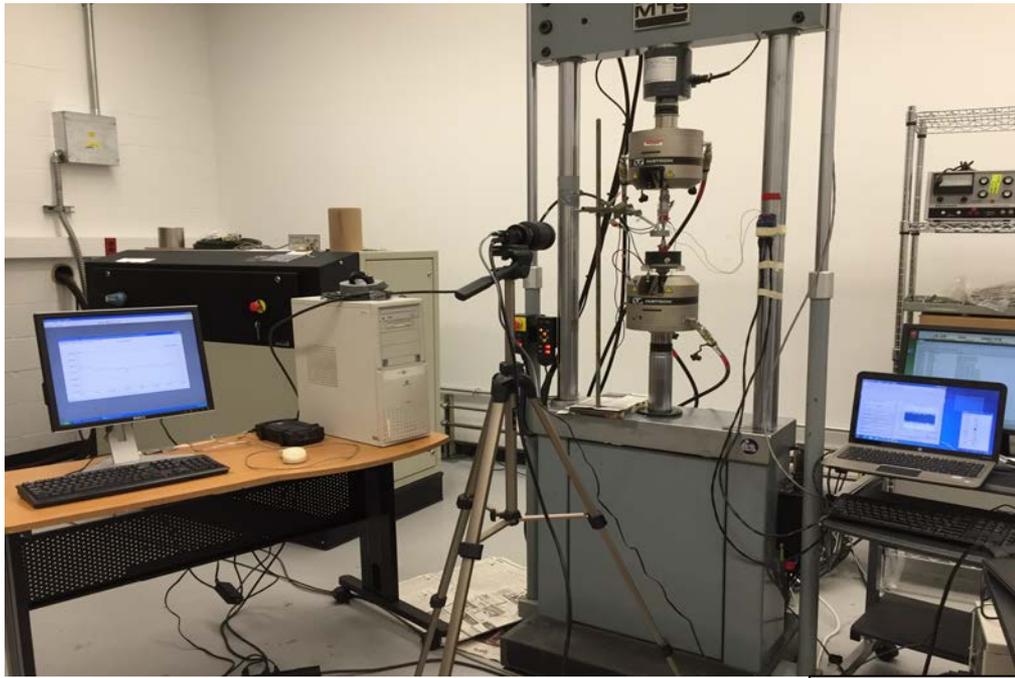
- Overview of Fatigue Crack and Acoustic Emission
- Experimental overview and examples of results
- Probabilistic Modeling
- Results
- Conclusions

Traditional Crack Growth/Detection Modeling

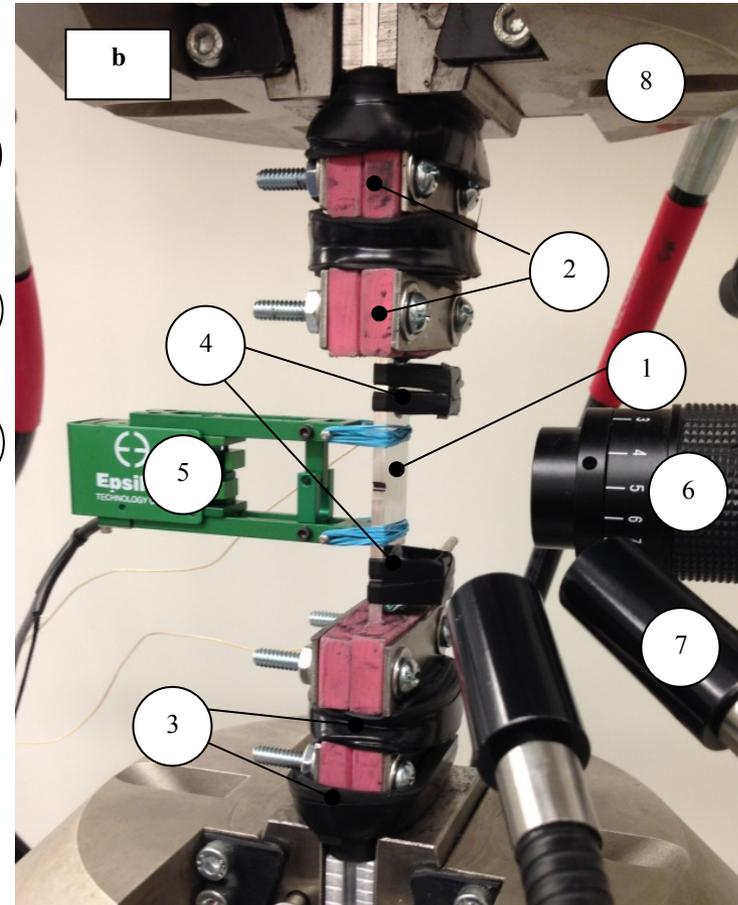
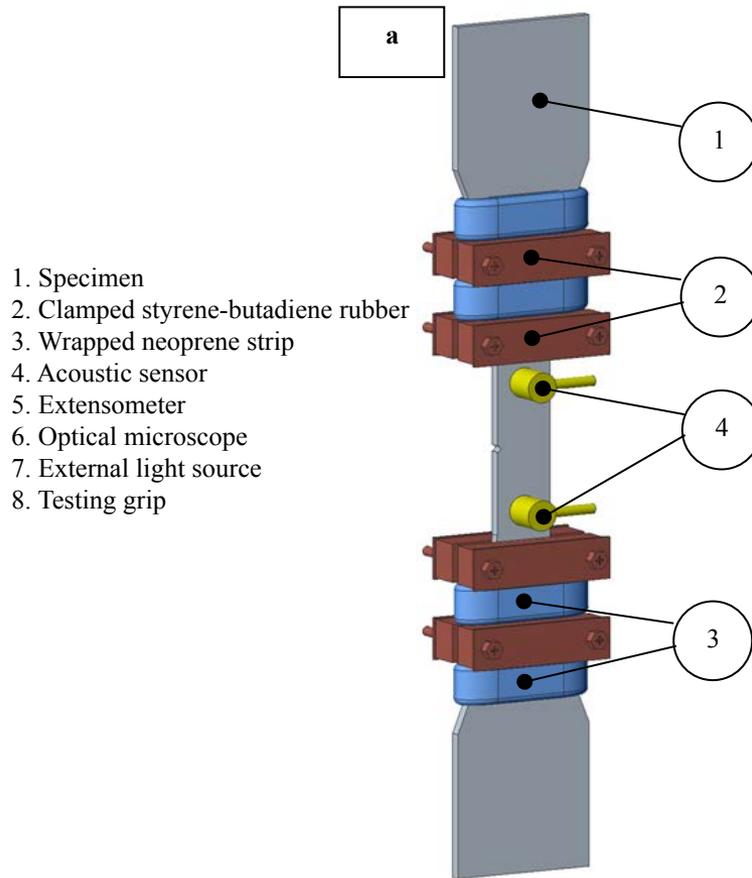
- Traditional empirical modeling of crack damage is typically used to model direct observable crack initiation and growth
- Recent advances in crack growth allows use of indirect precursors of crack such as acoustic emission (AE) for online monitoring
- Wide variety of crack growth and detection models, however these empirical models contain uncertainties:
 1. Model/Data Uncertainty
 2. Physical Variability
 3. Model Error
- Identification of these uncertainties are necessary to improve crack growth/detection models



Fatigue Testing with AE



Fatigue Testing with AE (Cont.)



Fatigue Testing and Test Example

- Sample Information:

- Test CSFs

- Frequency = 2 Hz
- Load Ratio = 0.5
- Min/Max Load = 6500/13000 N

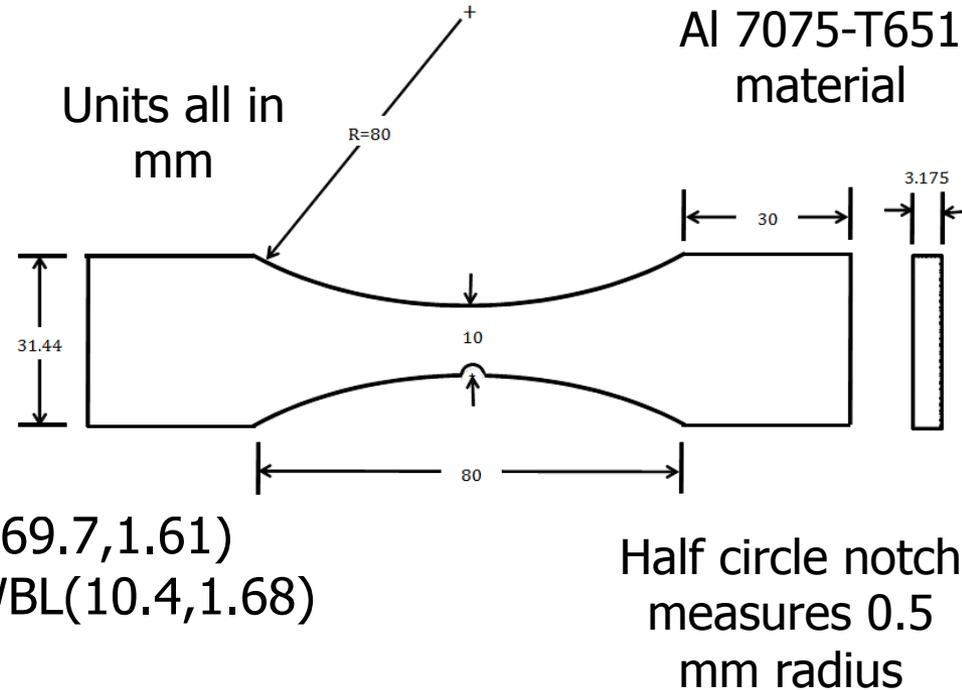
- Material CSFs

- Mean Grain Diameter – WBL(69.7,1.61)
- Mean Inclusion Diameter – WBL(10.4,1.68)

- Data

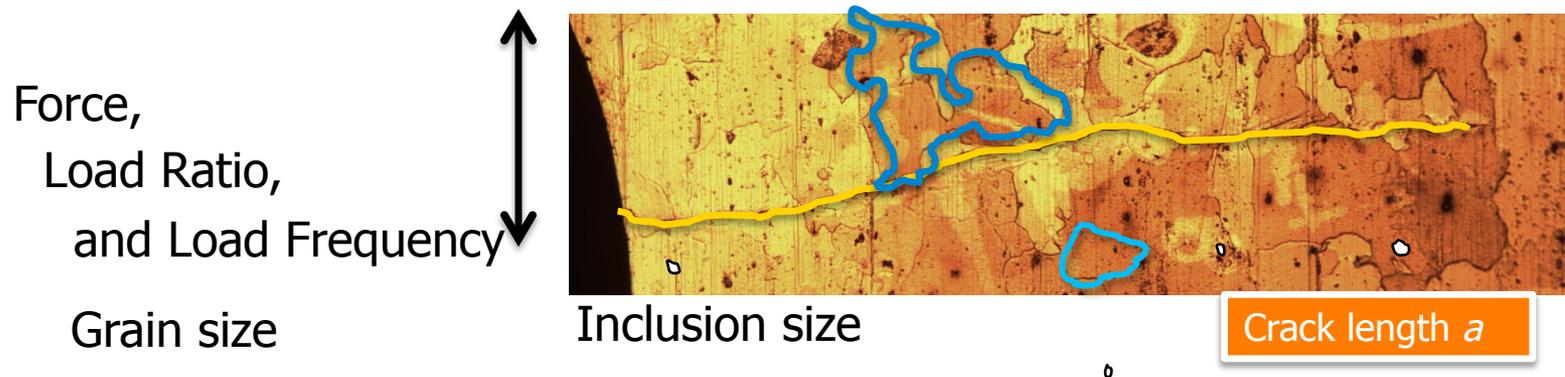
- 125 data collected (5 non-detections, 120 detections)
- 108 training data, 12 validation data

$$da/dN = \alpha \downarrow 1 \quad dc/dN \uparrow \alpha \downarrow 2$$



Introduction of CSFs and Applications in Crack Growth Modeling

- **Crack Shaping Factors (CSFs):**
 - Definition: Test or material based input properties that have direct bearing on the shape, length, and growth of the crack
 - Accounting minimize model uncertainties



- Several growth and detection models were tested through probabilistic Bayesian parameter estimation procedures

Likelihood Function for Bayesian Analysis

- Find the model parameters with the following likelihood function,

$$l(D=0,1; a \downarrow i=1, \dots, a \downarrow n \downarrow D, x \downarrow i=1, \dots, x \downarrow n \downarrow D, x \downarrow j=1, \dots, x \downarrow m \downarrow ND | A, B, P \downarrow FD) = \prod_{i=1}^{n \downarrow D} [(1 - P \downarrow FD) POD(D=1 | B, a \downarrow i > a \downarrow lth) f(a \downarrow i | A, x \downarrow i)] \prod_{j=1}^{m \downarrow ND} [1 - (1 - P \downarrow FD) \int_{a \downarrow lth}^{\infty} POD(D=1 | B, a > a \downarrow lth) f(a | A, x \downarrow j) da]$$

- Terms:

- A – crack growth model parameters
- B – crack detection model parameters
- $P \downarrow FD$ – probability of false detection
- a – crack length at time point i or j
- x – crack shaping factor vector pertaining to crack length $a \downarrow i$ or $a \downarrow j$
- $n \downarrow D$ – number of detection data points ($x \downarrow i=1, \dots, x \downarrow n \downarrow D; a \downarrow i=1, \dots, a \downarrow n \downarrow D$)
- $m \downarrow ND$ – number of non-detection data points ($x \downarrow j=1, \dots, x \downarrow m \downarrow ND; a \downarrow j=1=0, \dots, a \downarrow m \downarrow ND=0$)
- POD – probability of detection CDF
- f – crack propagation PDF
- D – detection state ($D=1$ detected/ $D=0$ not detected)

Crack POD Model Choices

- Lognormal POD Model

- $POD(a|\zeta_{\downarrow 0}, \zeta_{\downarrow 1}, a_{\downarrow lth}) = \int_{a_{\downarrow lth}}^{\infty} \frac{1}{(x - a_{\downarrow lth}) \sqrt{2\pi\zeta_{\downarrow 1}^2}} \exp\left\{-\frac{1}{2} \left[\ln\left(\frac{x - a_{\downarrow lth}}{\zeta_{\downarrow 1}}\right) - \zeta_{\downarrow 0}\right]^2\right\} dx$; $B = [\zeta_{\downarrow 0}, \zeta_{\downarrow 1}]$

- Log-logistic POD Model

- $POD(a|\beta_{\downarrow 0}, \beta_{\downarrow 1}, a_{\downarrow lth}) = \frac{\exp[\beta_{\downarrow 0} + \beta_{\downarrow 1} \ln(a - a_{\downarrow lth})]}{1 + \exp[\beta_{\downarrow 0} + \beta_{\downarrow 1} \ln(a - a_{\downarrow lth})]}$; $B = [\beta_{\downarrow 0}, \beta_{\downarrow 1}]$

- Logistic POD Model

- $POD(a|\eta_{\downarrow 0}, \eta_{\downarrow 1}, a_{\downarrow lth}) = \frac{1 - \exp(-\eta_{\downarrow 0} \eta_{\downarrow 1} (a - a_{\downarrow lth}))}{1 + \exp[\eta_{\downarrow 0} \eta_{\downarrow 1} (a - a_{\downarrow lth})]}$; $B = [\eta_{\downarrow 0}, \eta_{\downarrow 1}]$

- Weibull POD Model

- $POD(a|\alpha_{\downarrow 0}, \alpha_{\downarrow 1}, a_{\downarrow lth}) = 1 - \exp\left[-\left(\frac{a - a_{\downarrow lth}}{\alpha_{\downarrow 0}}\right)^{\alpha_{\downarrow 1}}\right]$; $B = [\alpha_{\downarrow 0}, \alpha_{\downarrow 1}]$

Crack Growth Model Choices

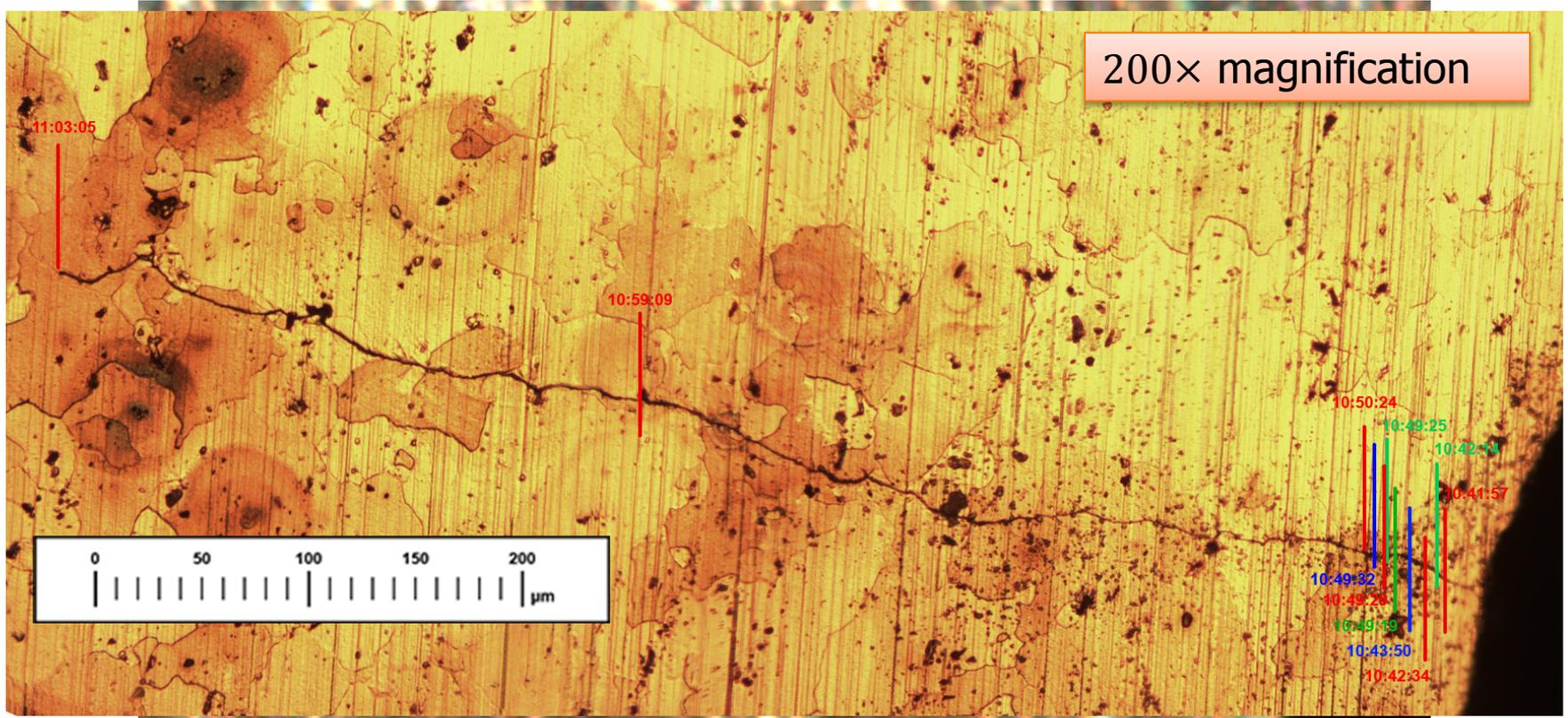
- All crack growth models fit to the lognormal PDF distribution,
 - $f(a|A, x) = 1/a\sigma\sqrt{2\pi} \exp[-1/2 (\ln a - \ln g(A, x) / \sigma)^2]$
where σ is the standard deviation
- Log-Linear Growth Direct Model
 - $\ln a = b + m \ln N$
- Acoustic Emission Growth Indirect Model
 - $a(N) = \{ \alpha I(N) + \beta \}$ & linear @ $\alpha I(N)^\beta$ & power
where $I(N)$ is a function of AE amplitude and cumulative counts
- Gaussian Process Regression (GPR) Growth Model
 - $a = g(x) = g([CSF_1, CSF_2, \dots, CSF_Q])$

More Details About the GPR Model

- $a \sim \text{NOR}[0, K([X], A)]$
 - where $K(\cdot)$ is the $M \times M$ covariance matrix or kernel matrix that correlates a and $[X]$
 - Kernel matrix are made up of kernel functions $k(x \downarrow i, x \downarrow j, A)$ taking two sets of CSF data $x \downarrow i$ and $x \downarrow j$ and the Gaussian crack length model parameters A
 - $k(x \downarrow i, x \downarrow j, A) = A \downarrow 1 + \sum_{q=1}^{\uparrow Q} A \downarrow q + 1 x \downarrow i, q x \downarrow j, q + A \downarrow 2 + 2 Q \exp[-\sum_{q=1}^{\uparrow Q} A \downarrow q + Q + 1 (x \downarrow i, q - x \downarrow j, q)^2] + A \downarrow 4 + 2 Q \sin^{-1} A \downarrow 3 + 2 Q \sum_{q=1}^{\uparrow Q} x \downarrow i, q x \downarrow j, q / \sqrt{(A \downarrow 3 + 2 Q \sum_{q=1}^{\uparrow Q} x \downarrow i, q x \downarrow j, q)^2} + A \downarrow 5 + 2 Q \delta \downarrow i, j$ where $\delta \downarrow i, j$ is a Dirac function



Fatigue Life Test Data Collection

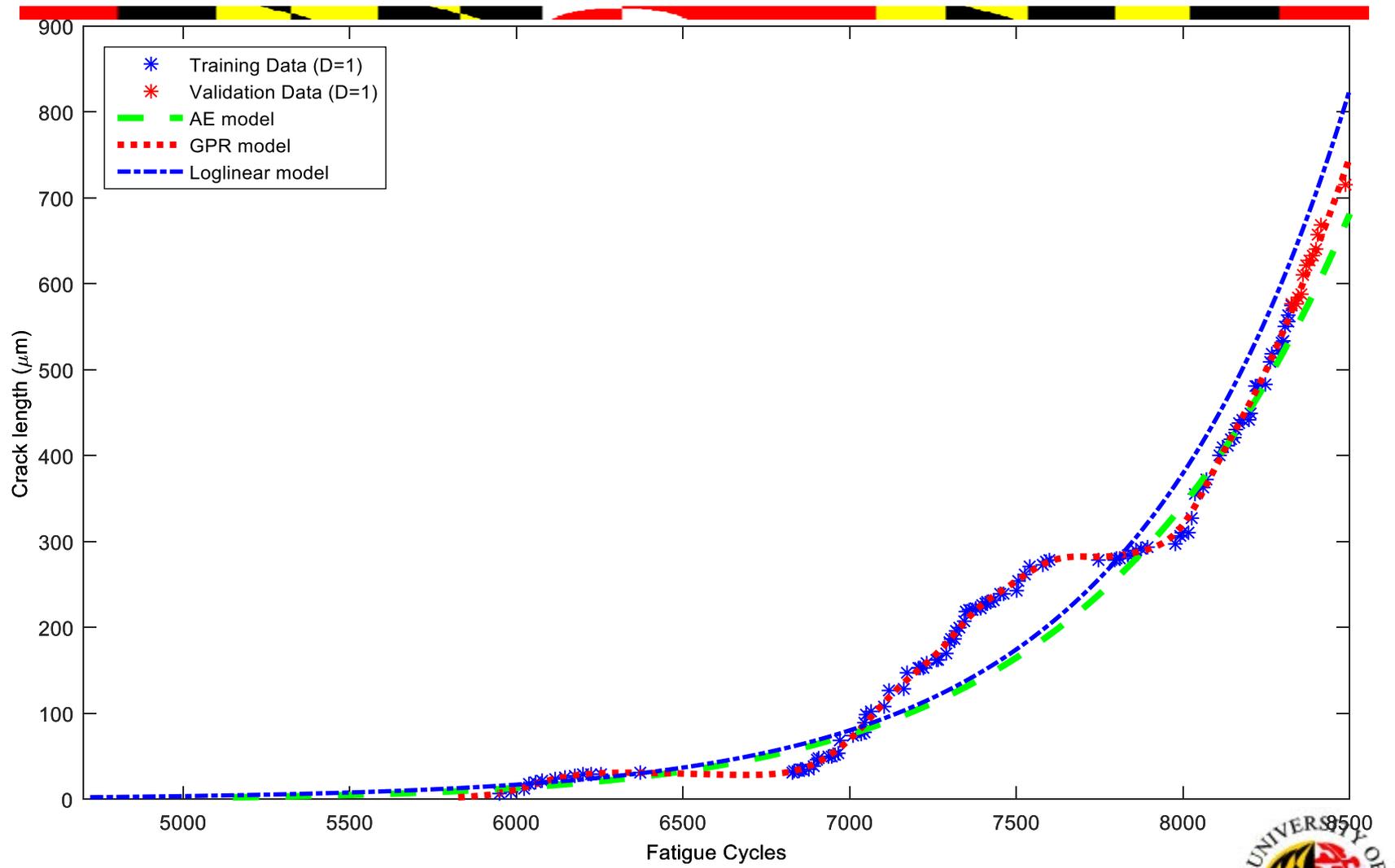


Measurement Error Considerations

	Log-Linear-Based Crack Length	AE-Based Crack Length
Mean Measurement Error	0.48	1.25
Model Error	51.9%	24.5%

- The model error between the true and estimated length is less for AE-Based crack length estimation than with the measured length estimation
- AE length measurement only overestimates the true length during early cycles

Results of Crack Growth Models Considered

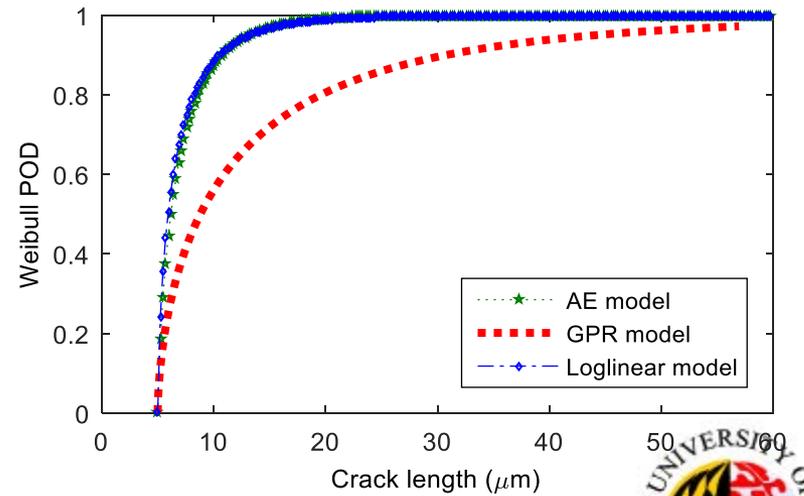
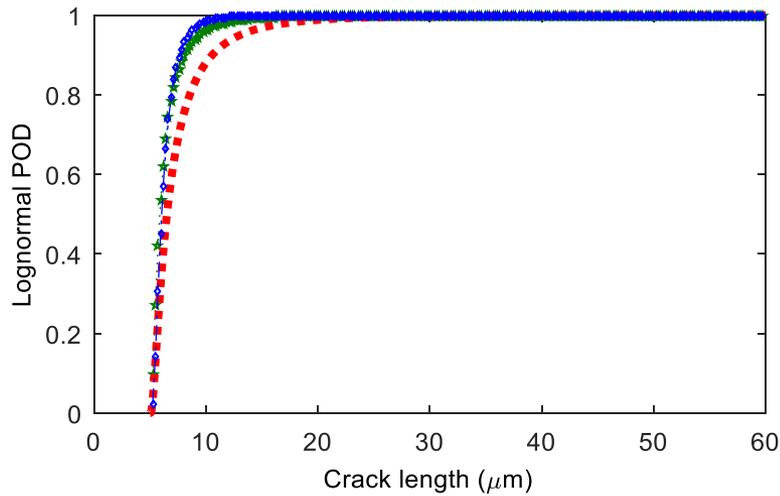
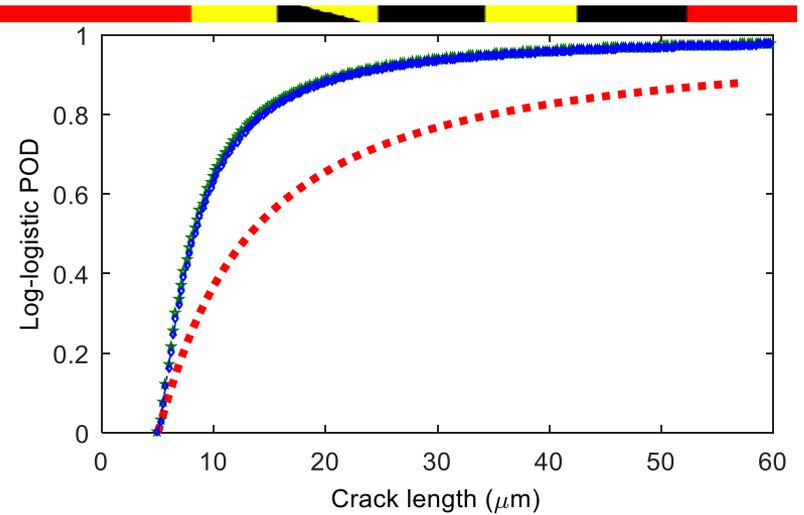
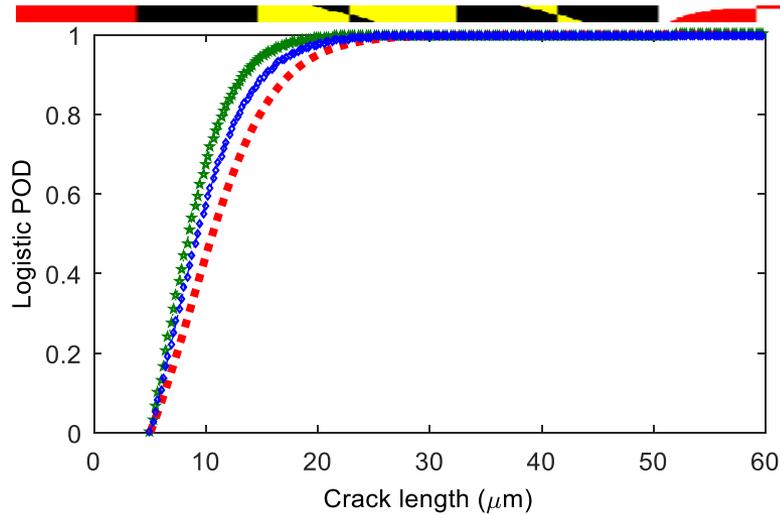


Crack Growth/Detection Model Results

Growth Model \ POD		Lognormal	Logistic	Log-Logistic	Weibull	AVERAGE
NMSE	Log-Linear	2.4	2.3	2.3	1.9	2.2
	AE	0.37	0.30	0.29	0.28	0.31
	GPR	0.042	0.041	0.041	0.041	0.042

- The GPR/Log-logistic pair has the smallest normalized mean square error (NMSE) of validation data
- Number of CSFs used understandably correlates to lower NMSE
 - GPR – 9 CSFs
 - AE – 3 CSFs
 - Log-linear – 1 CSF

POD Model Results



Conclusions



- AE-Based model
 - Has a lower error value than that of measured length model error
 - Has improved over previous studies from 42% to 24.5%
- By implementing the GPR on 12 CSFs pairs the model error could be reduced by a large sum
- The number of CSFs used directly impact the fitness and realism of the crack length model.



THANK YOU!

